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IN THE ABSTRACT:

A semiconductor test system is capable of time critical sequence generation using a general purpose operating system. The semiconductor test system includes a tester hardware for providing power sources and test patterns to a device under test, a host computer operated by a general purpose operating system, a configuration software for computing configuration data and timing data based on a test program, a device driver for providing a power trigger and a signal trigger to the tester hardware, and a hardware timer for producing an interrupt signal. The device driver causes to start the test pattern and to deactivate the power sources upon receiving the interrupt signal generated by the hardware timer and transferred from the host computer.